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INFORMATION DISCLOSURE STATEMENT	Case No.	Gammel 18-47-1-57
	Serial No.	
	Applicant:	P.L. Gammel, et al.
	Filing Date:	
	Group:	

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date
	AA	5,637,539	06/10/97	Hofmann et al.	438		01/16/96
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	AR	A.S. Gilmour, Jr., Microwave Tubes, Artech House, pp. 191-313 (1986).
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	BB	D.K. Lynn, et al., "Thermionic Integrated Circuits: Electronics For Hostile Environments", <u>IEEE Transactions on Nuclear Science</u> , Vol. NS-32, No. 6 (1985)
	BC	U.S. Patent Application Serial No. 09/236966 filed on January 25, 1999
	BD	U.S. Patent Application Serial No. 09/236933 filed on January 25, 1999
	BE	U.S. Patent Application Serial No. 09/296572 filed on April 22, 1999
	BF	U.S. Patent Application Serial No. 09/351537 filed on July 12, 1999
	BG	U.S. Patent Application Serial No. 09/512873 filed on February 25, 2000
	BH	U.S. Patent Application Serial No. 09/376457 filed on August 18, 1999

EXAMINER	DATE CONSIDERED

***Examiner:** Initial if reference considered, whether or not citation is in conformance with MPEP 609: Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.